

AO3423

P-Channel Enhancement Mode Field Effect Transistor



Units

General Description

The AO3423/L uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a load switch or in PWM applications. It is ESD protected. AO3423 and AO3423L are electrically identical.

- -RoHS Compliant
- -AO3423L is Halogen Free

Features

 $V_{DS}(V) = -20V$

 $I_D = -2 A$ $(V_{GS} = -10V)$

 $R_{DS(ON)}$ < $92m\Omega$ (V_{GS} = -10V)

 $R_{DS(ON)}$ < 118m Ω (V_{GS} = -4.5V)

 $R_{DS(ON)}$ < 166m Ω (V_{GS} = -2.5V)

ESD Rating: 2000V HBM



Absolute Maximum Ratings T_A=25°C unless otherwise noted



Parameter	Symbol	Maximum		
Drain-Source Voltage	V_{DS}	-20		
Gate-Source Voltage	V_{GS}	±12		
Continuous Drain T _A =25°C ^F		-2		
Current A T =70°CF		2		

Continuous Drain	T _A =25°C ^F		-2	
Current ^A	T _A =70°C ^F	I_D	-2	Α
Pulsed Drain Current ^B		I _{DM}	-8	
	T _A =25°C	D_	1.4	W
Power Dissipation A	T _A =70°C	P_{D}	0.9	VV
Junction and Storage	Temperature Range	T_J , T_{STG}	-55 to 150	°C

Thermal Characteristics						
Parameter		Symbol	Тур	Max	Units	
Maximum Junction-to-Ambient A	t ≤ 10s	В	65	90	°C/W	
Maximum Junction-to-Ambient ^A	Steady-State	$R_{ hetaJA}$	85	125	°C/W	
Maximum Junction-to-Lead ^C	Steady-State	$R_{\theta JL}$	43	60	°C/W	

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions		Min	Тур	Max	Units
STATIC F	PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	I _D =-250μA, V _{GS} =0V		-20			V
Zoro Coto Voltago Drain Current	Zero Gate Voltage Drain Current	V _{DS} =-16V, V _{GS} =0V				-0.5	4
I _{DSS}	Zelo Gate Voltage Dialii Guilelli		T _J =55°C			-2.5	μΑ
I _{GSS}	Gate-Body leakage current	V_{DS} =0V, V_{GS} =±10V				±1	μΑ
GSS	Gale-Body leakage current	V_{DS} =0V, V_{GS} =±12V				±10	μΑ
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS} I_{D}=-250 \mu A$		-0.7	-0.9	-1.4	V
$I_{D(ON)}$	On state drain current	V_{GS} =-4.5V, V_{DS} =-5V		-8			Α
R _{DS(ON)} Static Drain-Source On-Resistance		V _{GS} =-10V, I _D =-2A			76	92	mO
	T _J =125			90	108	mΩ	
DS(ON)	Static Dialii-Source Off-Resistance	V_{GS} =-4.5V, I_{D} =-2A			94	118	mΩ
		V_{GS} =-2.5V, I_D =-1A			128	166	mΩ
g _{FS}	Forward Transconductance	V_{DS} =-5V, I_{D} =-2A			6.8		S
V_{SD}	Diode Forward Voltage	I _S =-1A,V _{GS} =0V		-0.6	-0.78	-0.95	V
Is	Maximum Body-Diode Continuous Curre	rent				-1.8	Α
DYNAMIC	PARAMETERS						
C _{iss}	Input Capacitance				512	620	pF
C _{oss}	Output Capacitance	V _{GS} =0V, V _{DS} =-10V, f=1MHz			77		pF
C _{rss}	Reverse Transfer Capacitance				62		pF
R_g	Gate resistance	V _{GS} =0V, V _{DS} =0V, f=1MHz			9.2	13	Ω
SWITCHI	NG PARAMETERS		-		-		
Q_g	Total Gate Charge	V _{GS} =-4.5V, V _{DS} =-10V, I _D =-2A			5.5	6.6	nC
Q_{gs}	Gate Source Charge				0.8		nC
Q_{gd}	Gate Drain Charge				1.9		nC
t _{D(on)}	Turn-On DelayTime				5		ns
t _r	Turn-On Rise Time	V_{GS} =-10V, V_{DS} =-10V, R_L =5 Ω , R_{GEN} =3 Ω			6.7		ns
t _{D(off)}	Turn-Off DelayTime				28	_	ns
t _f	Turn-Off Fall Time]	Ī		13.5		ns
t _{rr}	Body Diode Reverse Recovery Time	I _F =-2A, dI/dt=100A/μs			9.8	12	ns
Q _{rr}	Body Diode Reverse Recovery Charge	I _F =-2A, dI/dt=100A/μs			2.7	_	nC

A: The value of R $_{\theta,JA}$ is measured with the device mounted on 1in 2 FR-4 board with 2oz. Copper, in a still air environment with T_A =25°C. The value in any given application depends on the user's specific board design. The current rating is based on the t \leq 10s thermal resistance rating.

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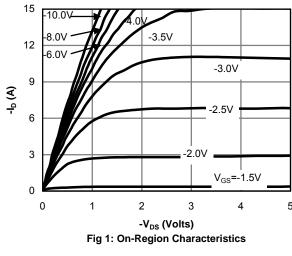
B: Repetitive rating, pulse width limited by junction temperature. C. The R $_{\theta JA}$ is the sum of the thermal impedence from junction to lead R $_{\theta JL}$ and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using $<300 \,\mu s$ pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in ² FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The SOA curve provides a single pulse rating.

F. The maximum current rating is limited by bond-wires.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



2 3 4 5 0 0.5 1 1.5 2
-V_{DS} (Volts) -V_{GS}(Volts)

10

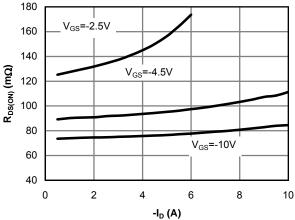
8

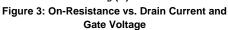
-I_D(A)

4

2

 V_{DS} =-5V





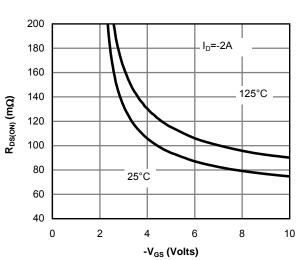
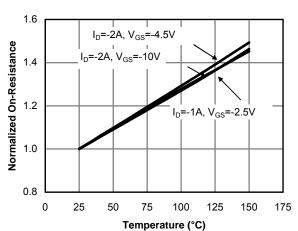


Figure 5: On-Resistance vs. Gate-Source Voltage



125°C

Figure 2: Transfer Characteristics

25°C

2.5

3

3.5

Figure 4: On-Resistance vs. Junction Temperature

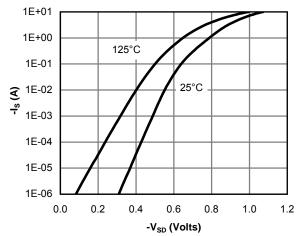


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

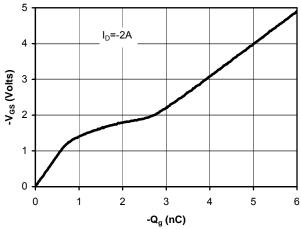


Figure 7: Gate-Charge Characteristics

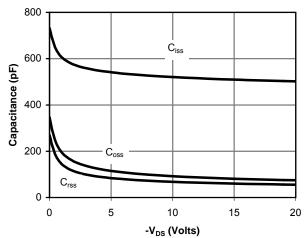


Figure 8: Capacitance Characteristics

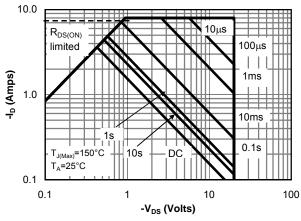


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

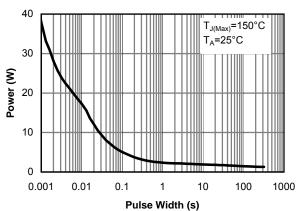


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

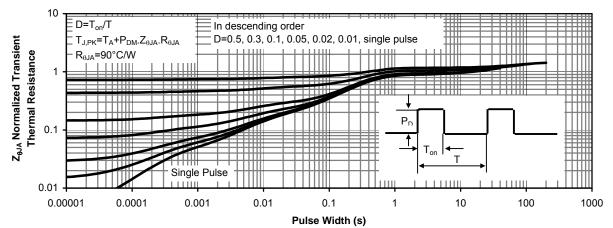


Figure 11: Normalized Maximum Transient Thermal Impedance